

Subject: PC**Date:** Mon, 14 Dec 1998 11:30:27 -0500**From:** oetech@fccsun07w.fcc.gov (OET)**To:** mullenr@bellatlantic.net

To: Richard Mullen, Safety & Compliance Consulting
From: Joe Dichoso
 jdichoso@fcc.gov
 FCC Application Processing Branch

Re: FCC ID EUNC2**Applicant:**

First International Computer Inc

Correspondence Reference Number: 5122

731 Confirmation Number: EA92357

Date of Original E-Mail: 12/14/1998

GTK 98-0017

1) Please send in Photo's of the device, both sides of all circuit boards.

The items indicated above must be submitted before processing can continue on the above referenced application. Failure to provide the requested information within 60 days of the original e-mail date may result in application dismissal pursuant to Section 2.917 (c) and forfeiture of the filing fee pursuant to section 1.1106.

DO NOT reply to this e-mail by using the Reply button. In order for your response to be processed expeditiously, you must upload your response via the Internet at www.fcc.gov, Electronic Filing, OET Equipment Authorization Electronic Filing. If the response is submitted through Add Attachments, in order to expedite processing, a message which informs the processing staff that a new exhibit has been submitted must also be submitted via Submit Correspondence. Also, please note that partial responses increase processing time and should not be submitted.

Any questions about the content of this correspondence should be directed to the e-mail address listed below the name of the sender.

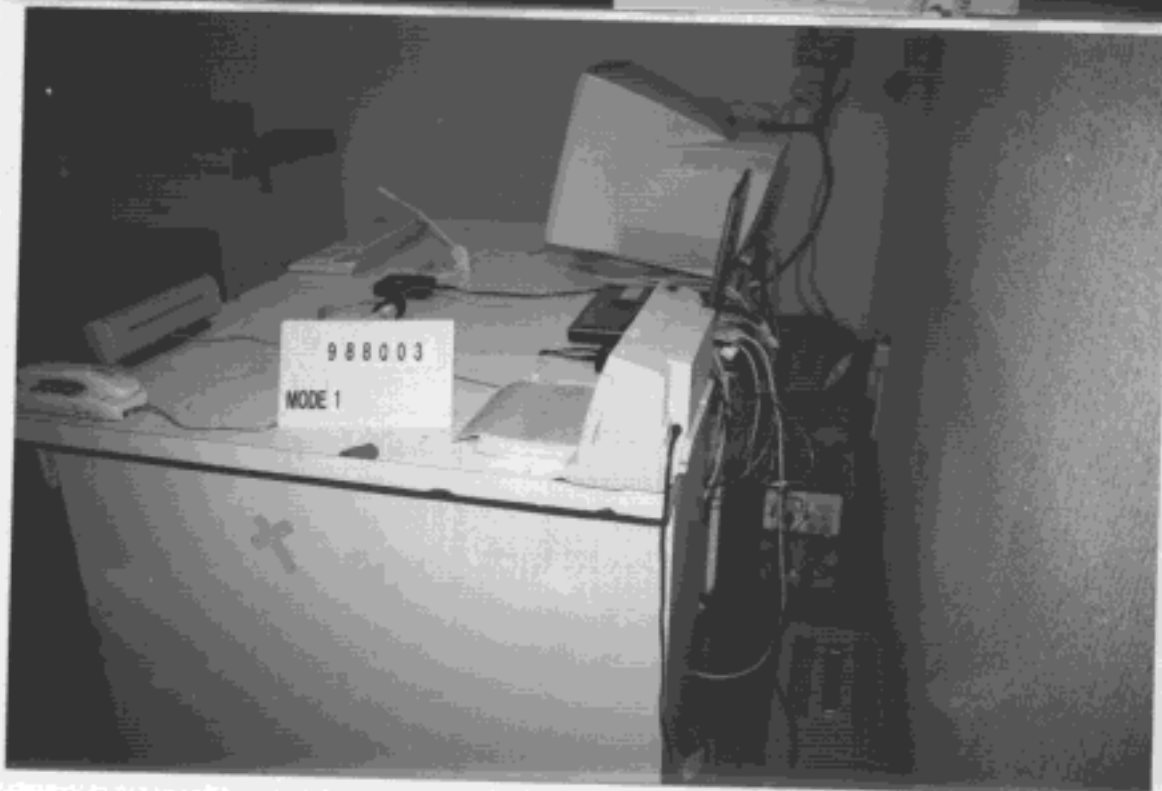
Requested Oetech again on 1/18/99 to send lost photos.

GTK98-F017

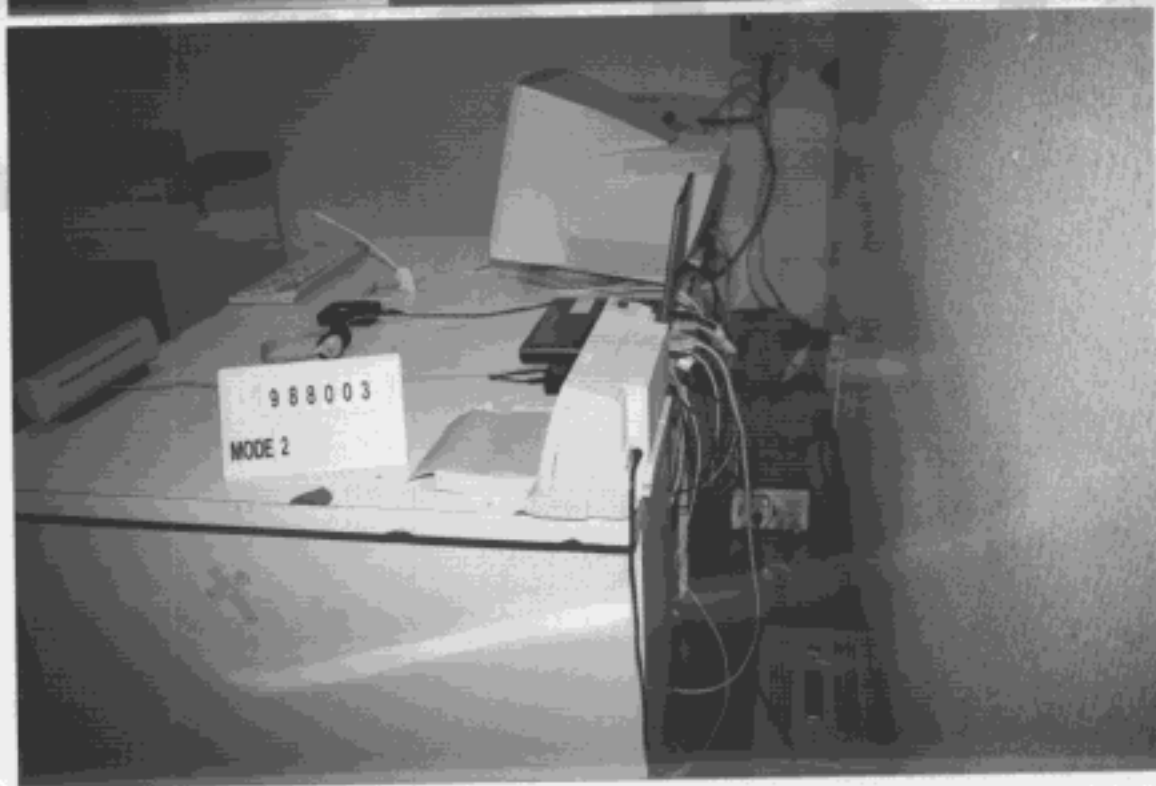
5. Photographs

5.1 Test Photographs

1. FRONT VIEW OF CONDUCTED TEST(Mode 1)
2. BACK VIEW OF CONDUCTED TEST(Mode 1)



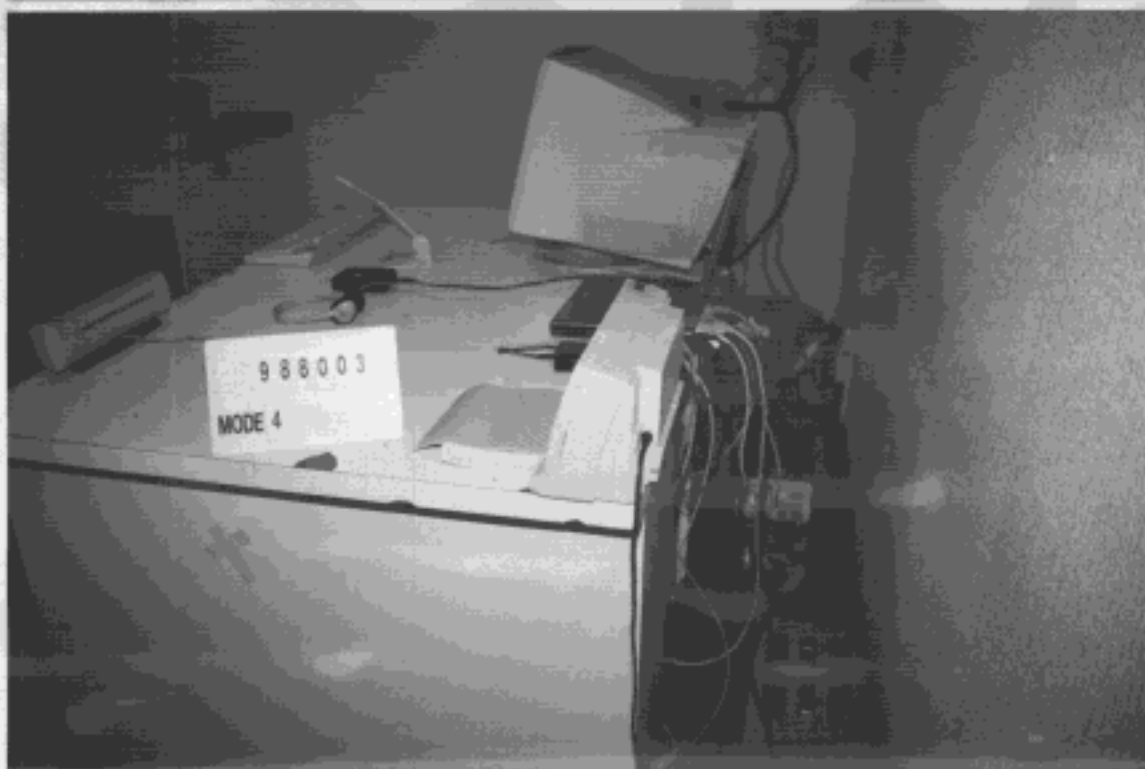
3. FRONT VIEW OF CONDUCTED TEST(Mode 2)
4. BACK VIEW OF CONDUCTED TEST(Mode 2)



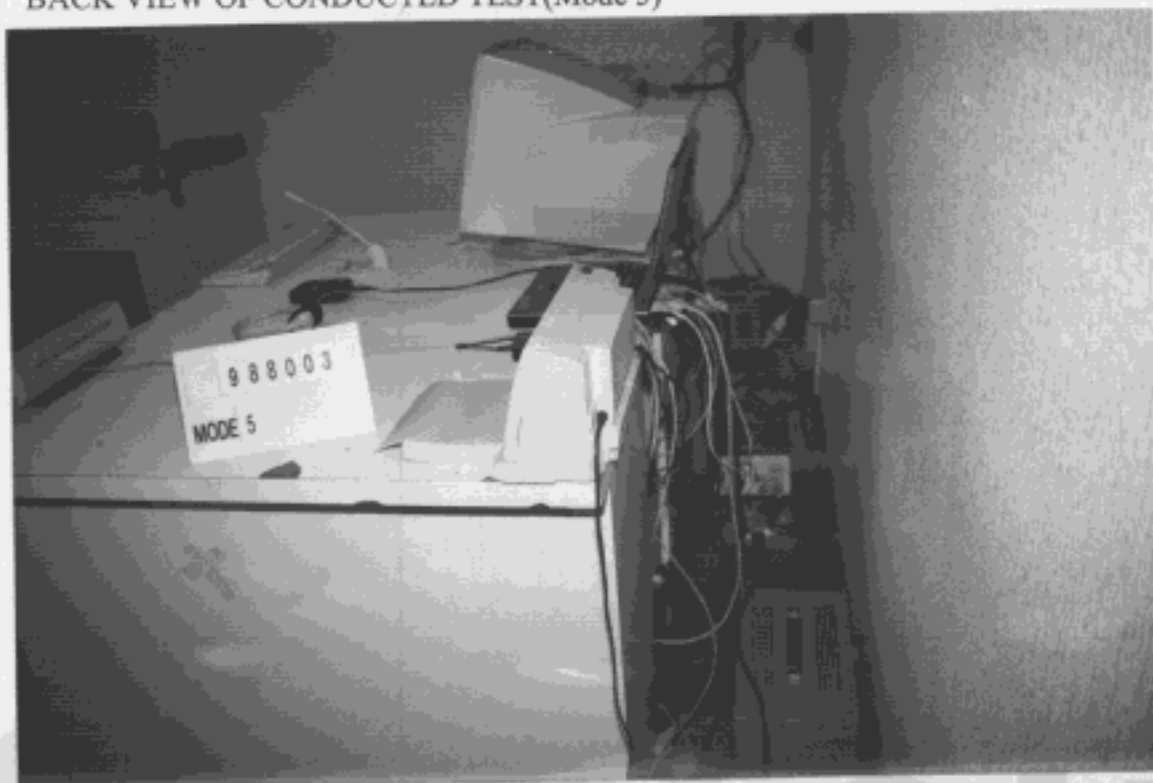
5. FRONT VIEW OF CONDUCTED TEST(Mode 3)
6. BACK VIEW OF CONDUCTED TEST(Mode 3)



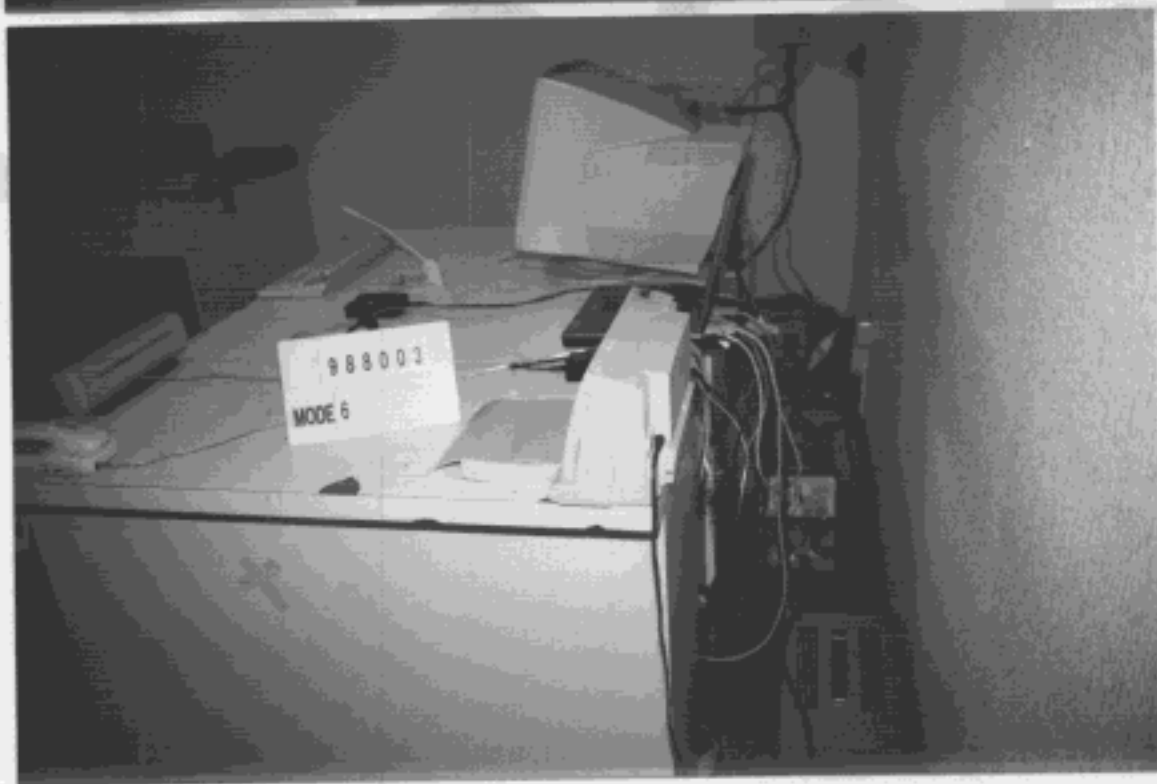
7. FRONT VIEW OF CONDUCTED TEST(Mode 4)
8. BACK VIEW OF CONDUCTED TEST(Mode 4)



9. FRONT VIEW OF CONDUCTED TEST(Mode 5)
10. BACK VIEW OF CONDUCTED TEST(Mode 5)



11. FRONT VIEW OF CONDUCTED TEST(Mode 6)
12. BACK VIEW OF CONDUCTED TEST(Mode 6)



13. FRONT VIEW OF CONDUCTED TEST(Mode 7)
14. BACK VIEW OF CONDUCTED TEST(Mode 7)



15. FRONT VIEW OF RADIATED TEST(Mode 1)
16. BACK VIEW OF RADIATED TEST(Mode 1)



17. FRONT VIEW OF RADIATED TEST(Mode 2)
18. BACK VIEW OF RADIATED TEST(Mode 2)



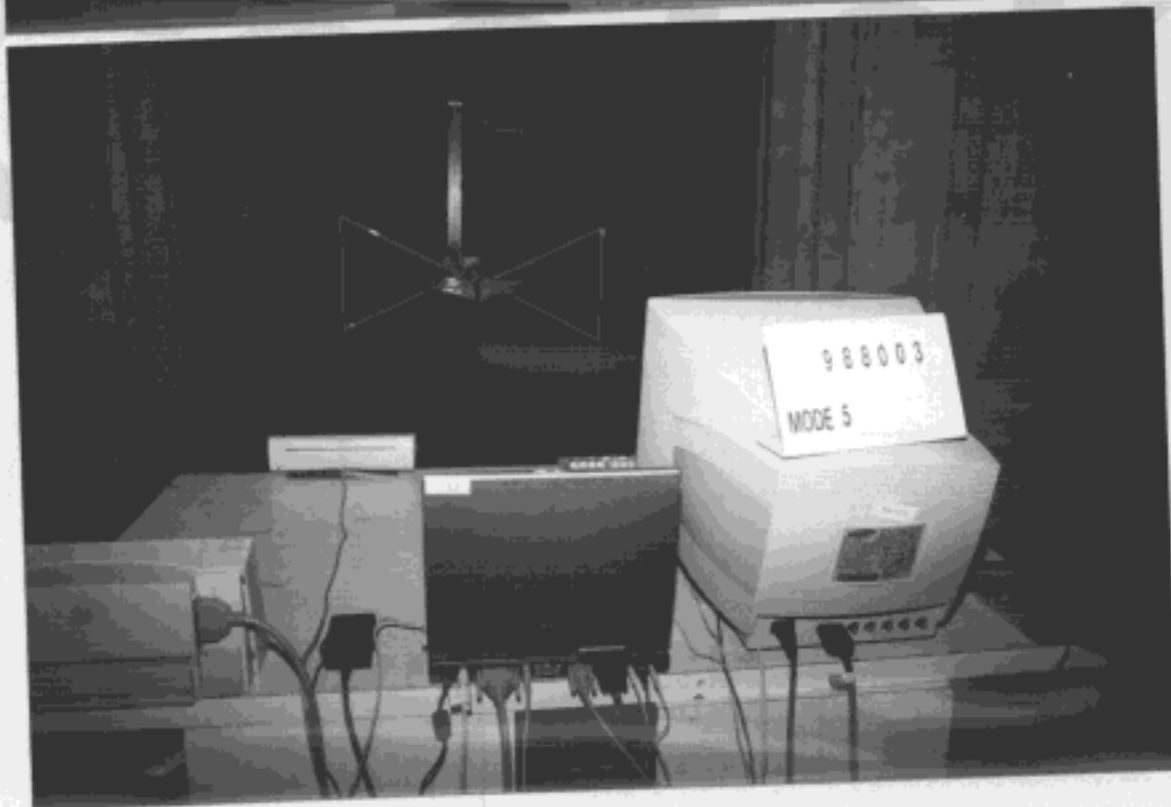
19. FRONT VIEW OF RADIATED TEST(Mode 3)
20. BACK VIEW OF RADIATED TEST(Mode 3)



21. FRONT VIEW OF RADIATED TEST(Mode 4)
22. BACK VIEW OF RADIATED TEST(Mode 4)



23. FRONT VIEW OF RADIATED TEST(Mode 5)
24. BACK VIEW OF RADIATED TEST(Mode 5)



25. FRONT VIEW OF RADIATED TEST(Mode 6)
26. BACK VIEW OF RADIATED TEST(Mode 6)

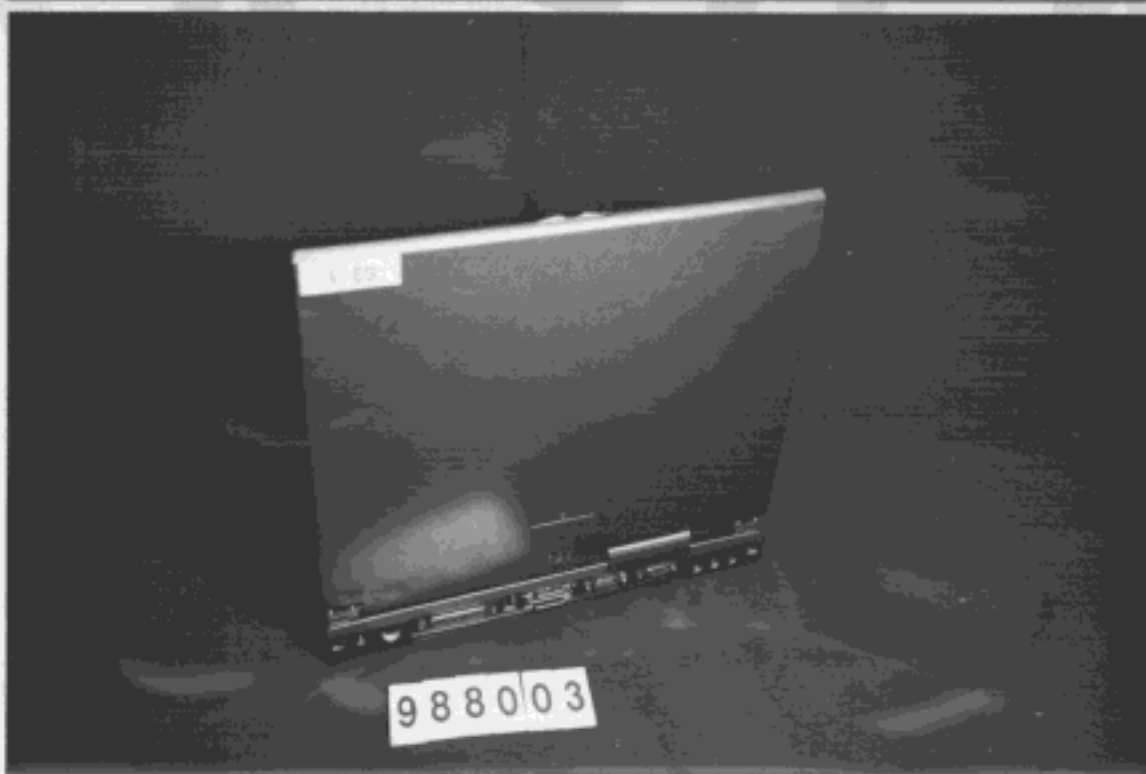


- 27. FRONT VIEW OF RADIATED TEST(Mode 7)
- 28. BACK VIEW OF RADIATED TEST(Mode 7)



6. EUT Detail Photographs

1. FRONT VIEW OF NOTEBOOK PERSONAL COMPUTER
2. BACK VIEW OF NOTEBOOK PERSONAL COMPUTER



3. INNER VIEW NOTEBOOK PERSONAL COMPUTER



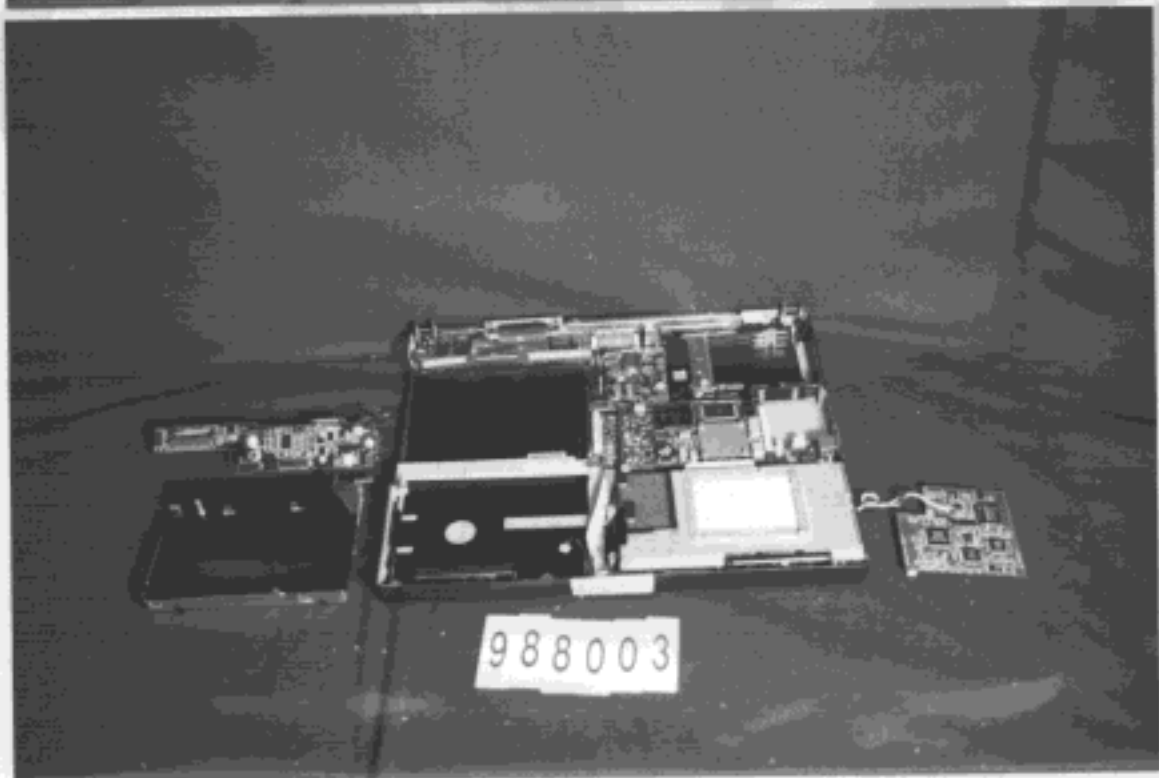
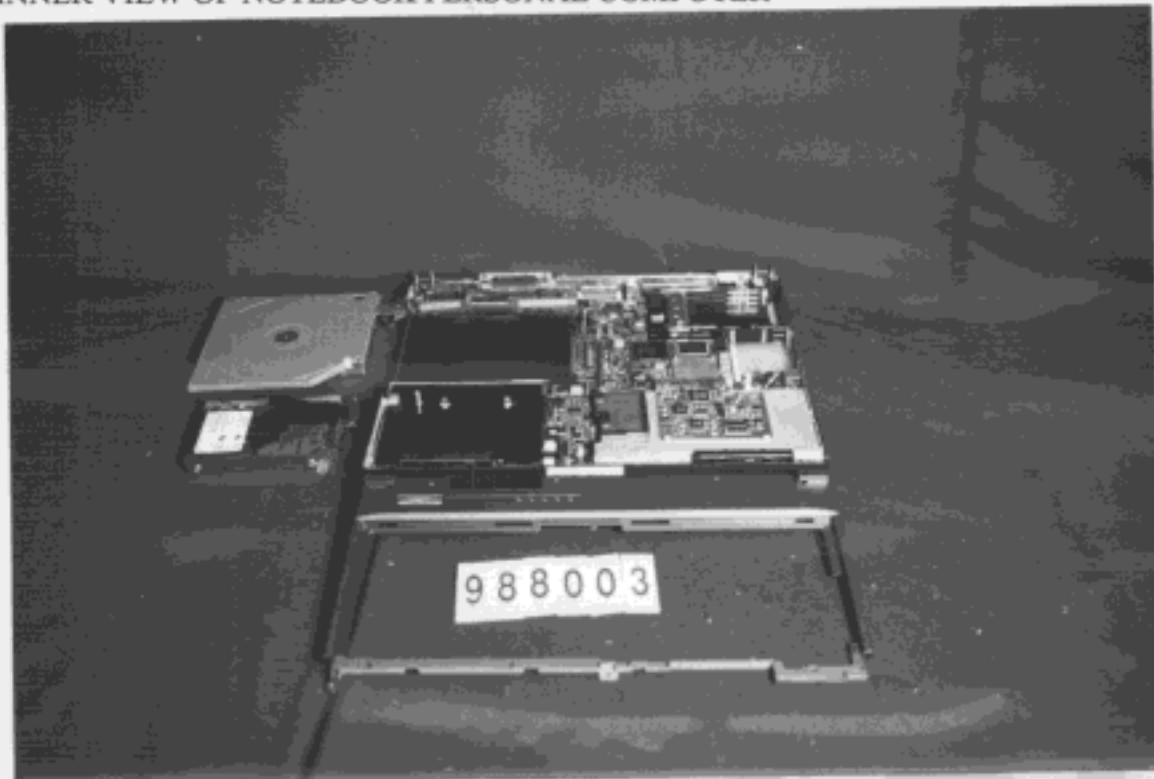
Ges / ek

4. INNER VIEW OF NOTEBOOK & KEYBOARD REMOVE
5. INNER VIEW OF NOTEBOOK & KEYBOARD REMOVE

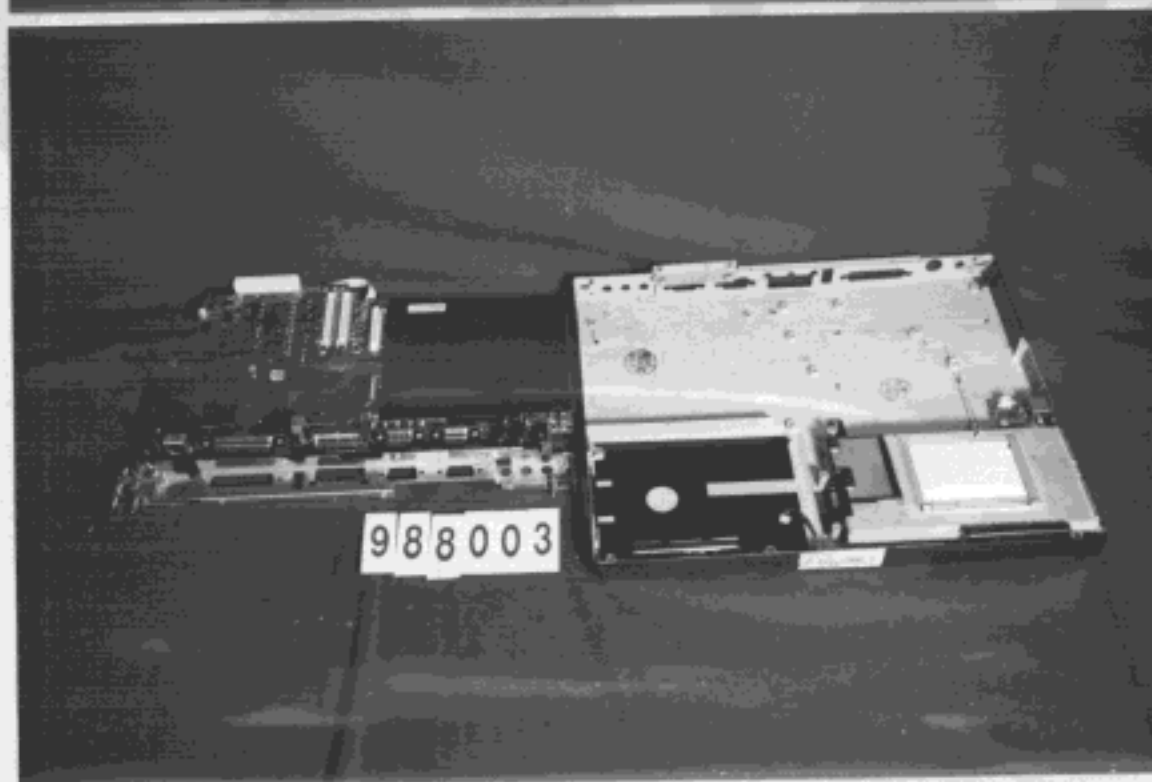
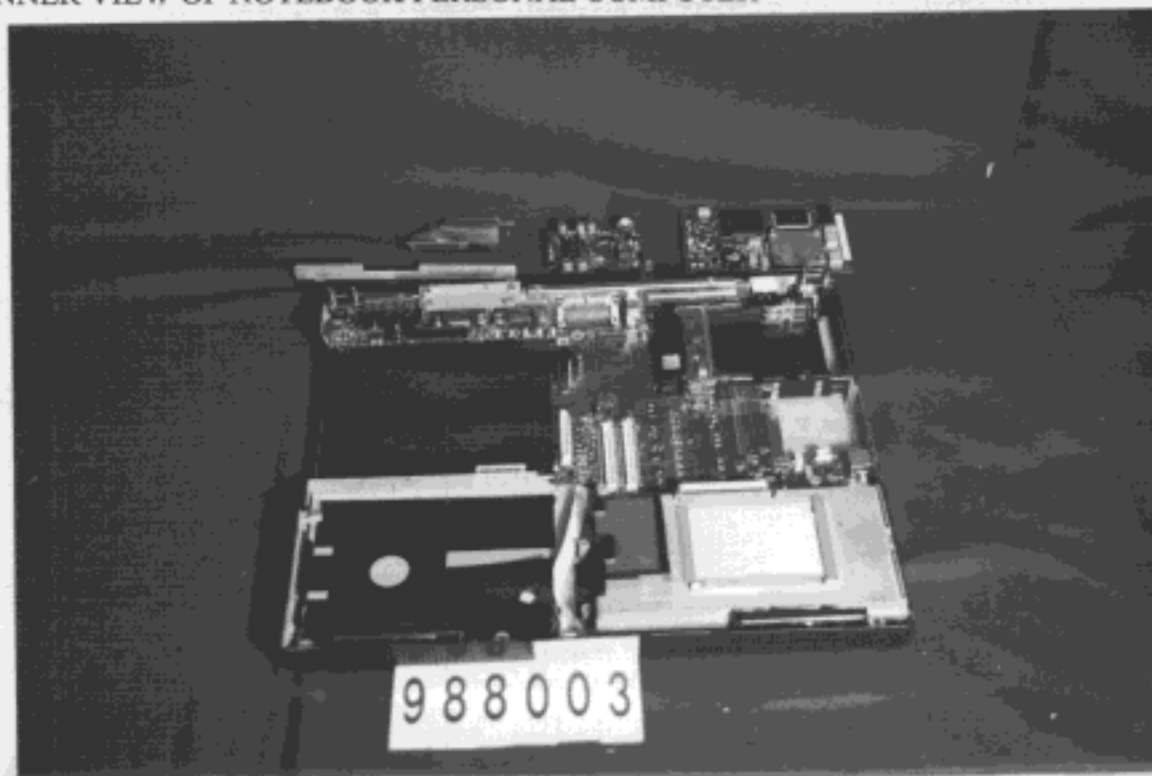


6. INNER VIEW OF NOTEBOOK PERSONAL COMPUTER

7. INNER VIEW OF NOTEBOOK PERSONAL COMPUTER

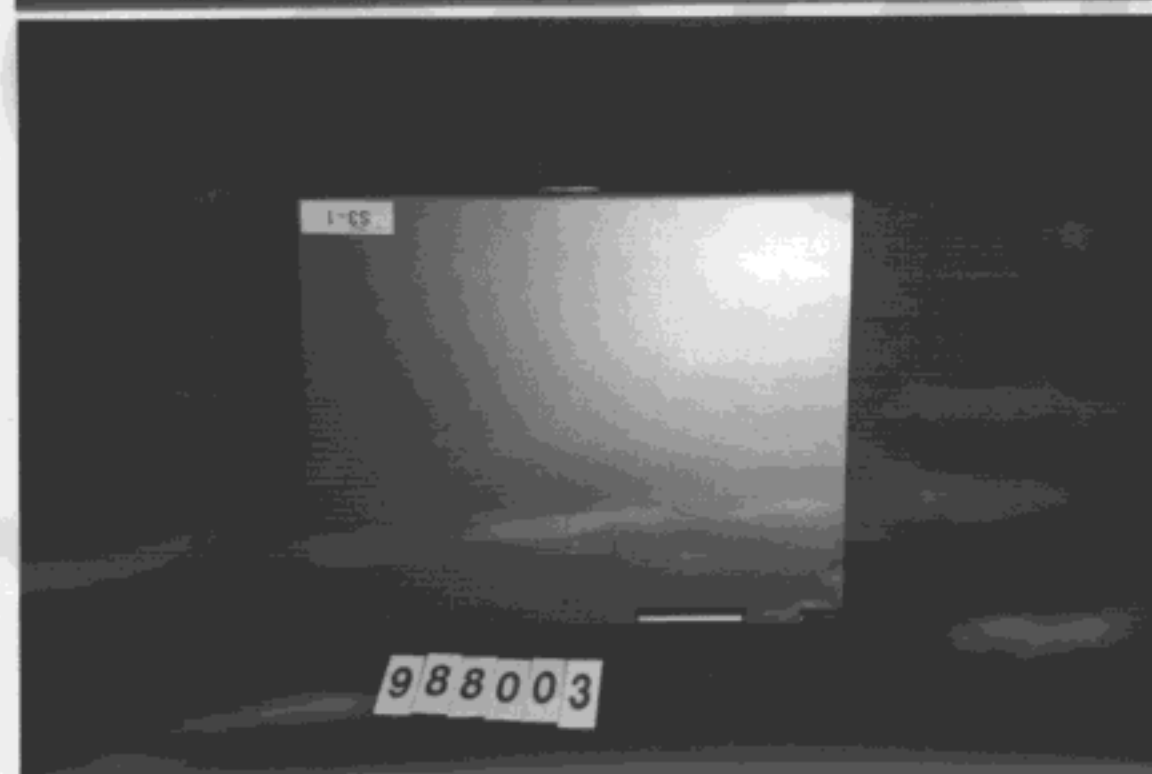
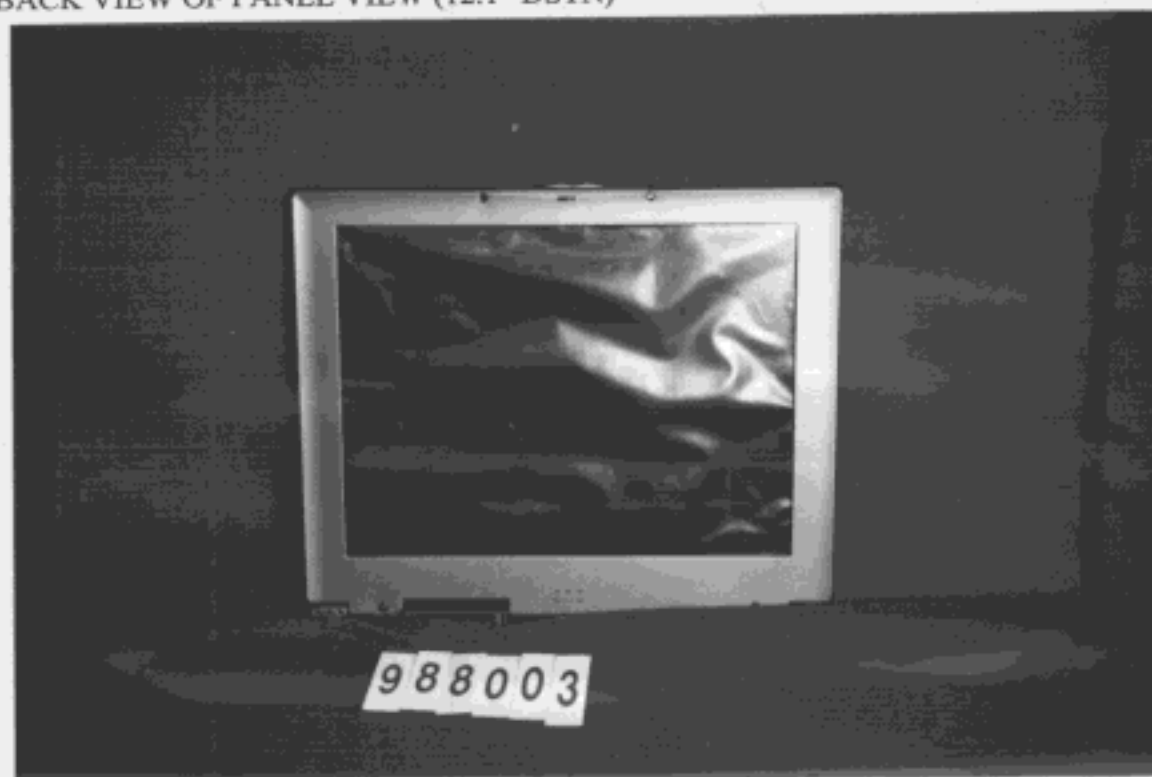


8. INNER VIEW OF NOTEBOOK PERSONAL COMPUTER
9. INNER VIEW OF NOTEBOOK PERSONAL COMPUTER



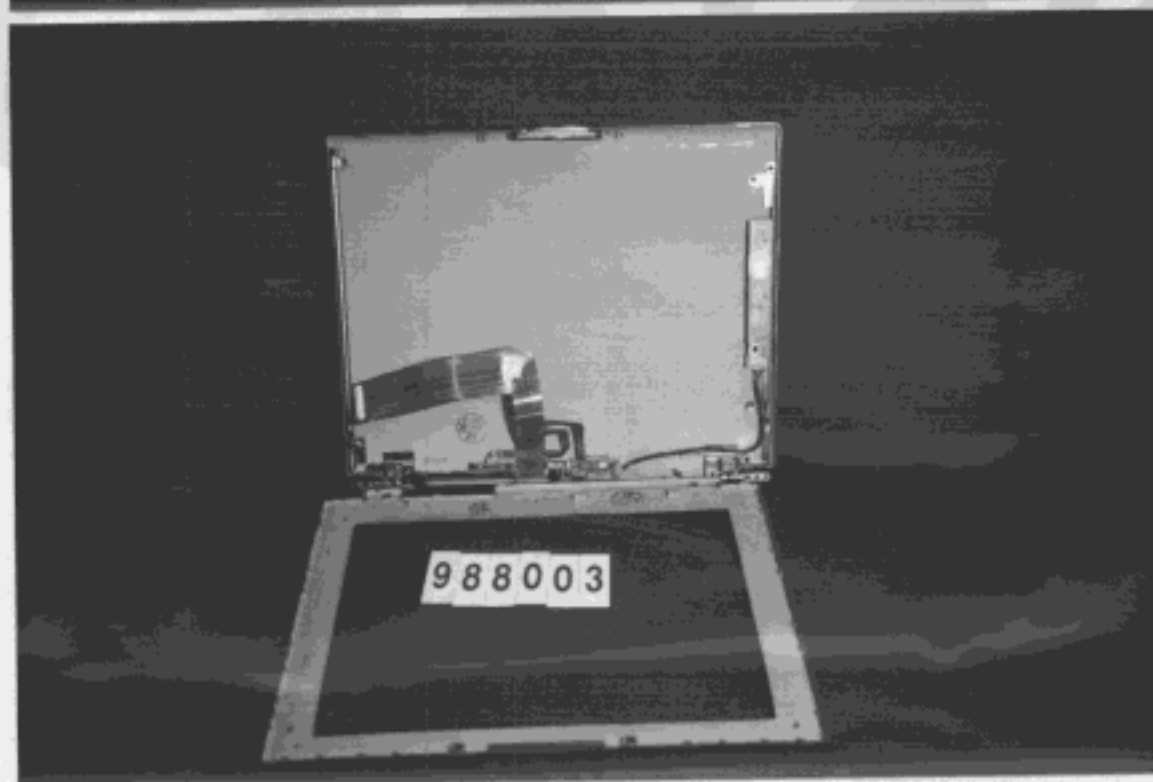
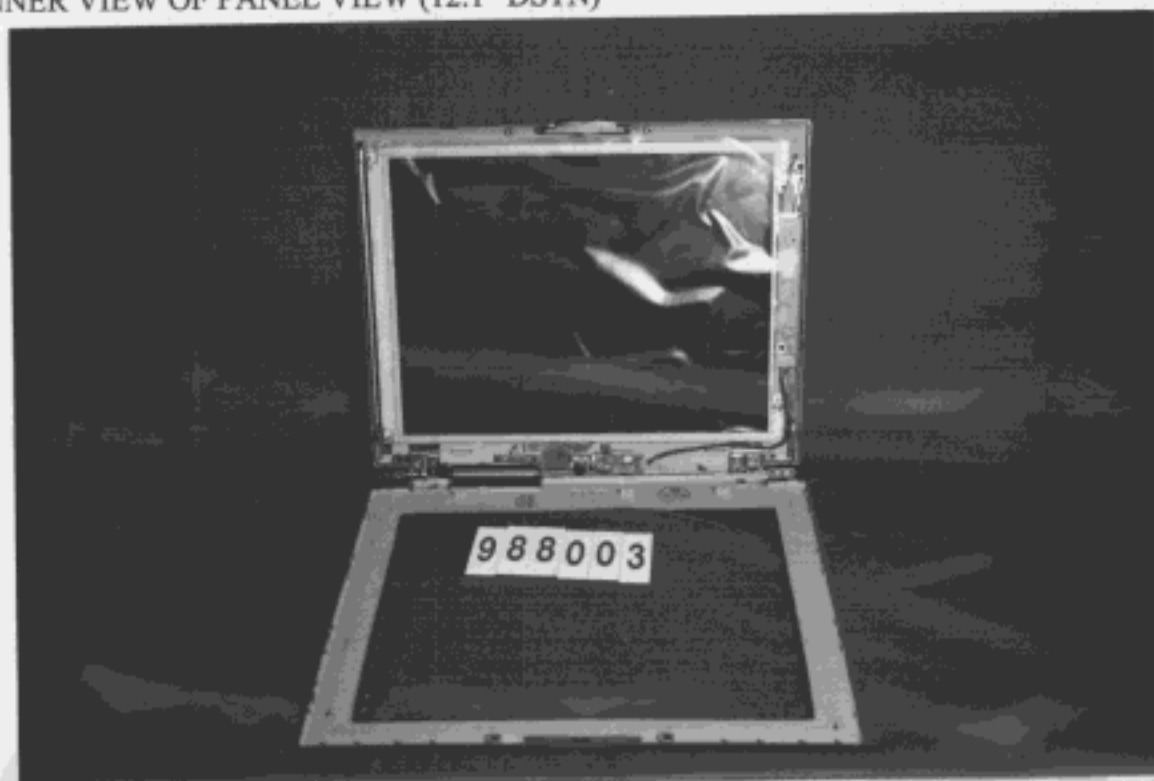
10. FRONT VIEW OF PANEL VIEW (12.1" DSTN)

11. BACK VIEW OF PANEL VIEW (12.1" DSTN)



12. INNER VIEW OF PANEL VIEW (12.1" DSTN)

13. INNER VIEW OF PANEL VIEW (12.1" DSTN)



14. FRONT VIEW OF PANEL VIEW (12.1" TFT)

15. BACK VIEW OF PANEL VIEW (12.1" TFT)

